2TRIG

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- Two Precision Timing Circuits per Package
- Astable or Monostable Operation
- TTL-Compatible Output Can Sink or Source Up to 150 mA
- Active Pullup or Pulldown
- Designed to be Interchangeable With Signetics NE556, SA556, and SE556
 - Applications Include:
 Precision Timers From Microseconds to Hours
 - Pulse-Shaping Clrcuits
 - Missing-Pulse Detectors
 - Tone-Burst Generators
 - Pulse-Width Modulators
 - Pulse-Position Modulators
 - Sequential Timers
 - Pulse Generators
 - Frequency Dividers
 - Application Timers
 - Industrial Controls
 - Touch-Tone Encoders

description

NE556, SA556 ... D, OR N PACKAGE SE556 ... J PACKAGE (TOP VIEW) 1DISCH[14 🛛 V_{CC} 1THRES 13 2DISCH 2 1CONT 12 2THRES 3 1RESET [] 4 2CONT 11 10UT [5 10 2RESET 1TRIG 1 20UT 6 9

GND [

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These devices provide two independent timing circuits of the NE555, SA555, or SE555 type in each package. These circuits can be operated in the astable or the monostable mode with external resistor-capacitor (RC) timing control. The basic timing provided by the RC time constant can be controlled actively by modulating the bias of the control-voltage input.

The threshold (THRES) and trigger (TRIG) levels are normally two-thirds and one-third, respectively, of V_{CC} . These levels can be altered by using the control-voltage (CONT) terminal. When the trigger input falls below trigger level, the flip-flop is set and the output goes high. If the trigger input is above the trigger level and the threshold input is above the threshold level, the flip-flop is reset and the output is low. The reset (RESET) input can override all other inputs and can be used to initiate a new timing cycle. When the reset input goes low, the flip-flop is reset and the output goes low. When the output is low, a low-impedance path is provided between the discharge (DISCH) terminal and ground (GND).

The NE556 is characterized for operation from 0°C to 70°C. The SA556 is characterized for operation from –40°C to 85°C, and the SE556 is characterized for operation over the full military range of –55°C to 125°C.

		PA	CKAGED DEVICES	
TA	V _T (MAX) V _{CC} = 15 V	SMALL OUTLINE (D)	CERAMIC DIP (J)	PLASTIC DIP (N)
0°C to 70°C	11.2 V	NE556D	-	NE556N
-40°C to 85°C	11.2 V	SA556D	-	SA556N
–55°C to 125°C	10.6 V	-	SE556J	-

AVAILABLE OPTIONS

The D package is available taped and reeled. Add the suffix R to the device type (e.g., NE556DR).

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



NE556, SA556, SE556 DUAL PRECISION TIMERS

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(each timer)								
RESET	TRIGGER VOLTAGE [†]	THRESHOLD VOLTAGE [†]	OUTPUT	DISCHARGE SWITCH				
Low	Irrelevant	Irrelevant	Low	On				
High	< 1/3 V _{DD}	Irrelevant	High	Off				
High	> 1/3 V _{DD}	> 2/3 V _{DD}	Low	On				
High	> 1/3 V _{DD}	> 2/3 V _{DD}	As previously established					

FUNCTION TABLE

[†] Voltage levels shown are nominal.

functional block diagram, each timer



RESET can override TRIG, which can override THRES.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC} (see Note 1) Input voltage (CONT, RESET, THRES, and TRIG) Output current	V _{CC}
Continuous total dissipation	
Package thermal impedance, θ_{JA} (see Note 2): D package	
	80°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds: J package .	300°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: D or N packa	ge 260°C
Storage temperature range, T _{stg}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to network ground terminal.

2. The package thermal impedance is calculated in accordance with JESD 51.

DISSIPATION RATING TABLE

	PACKAGE	$\begin{array}{c} \text{TA} \leq 25^{\circ}\text{C} \\ \text{POWER RATING} \end{array} \begin{array}{c} \text{DERATING FACTOR} \\ \text{ABOVE } T_{A} = 25^{\circ}\text{C} \end{array}$		T _A = 70°C POWER RATING	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING		
L	J	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW		



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recommended operating conditions

		MIN	MAX	UNIT
	NE556, SA556	4.5	16	V
Supply voltage, V _{CC}	SE556	4.5	18	v
Input voltage (CONT, RESET, THRES, and TRIG), VI				V
Output current, IO			±200	mA
	NE556	0	16 V 18 V V _{CC} V ±200 mA 70	
Operating free-air temperature, T _A	SA556	-40	85	°C
	SE556	-55	125	

electrical characteristics, V_{CC} = 5 V to 15 V, T_A = 25°C (unless otherwise noted)

	PARAMETER		TEST CONDITIONS		NE556, SA556			SE556			
		TEST CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
\/_	Thread and walks as lowed	V _{CC} = 15 V		8.8	10	11.2	9.4	10	10.6	V	
VT	Threshold voltage level	V _{CC} = 5 V		2.4	3.3	4.2	2.7	3.3	4	v	
Ι _Τ	Threshold current (see Note 3)				30	250		30	250	nA	
\/		V _{CC} = 15 V		4.5	5	5.6	4.8	5	5.2	V	
VTRIG	Trigger voltage level	$V_{CC} = 5 V$		1.1	1.67	2.2	1.45	1.67	1.9	V	
ITRIG	Trigger current	TRIG at 0 V			0.5	2		0.5	0.9	μΑ	
VRESET	Reset voltage level			0.3	0.7	1	0.3	0.7	1	V	
	SET Reset current	RESET at VC	C		0.1	0.4		0.1	0.4		
RESET	Reset current	RESET at 0 V	/		-0.4	1.5		-0.4	-1	mA	
IDISCH	Discharge switch off-state current				20	100		20	100	nA	
		V _{CC} = 15 V		9	10	11	9.6	10	10.4	V	
VCONT	Control voltage (open circuit)	V _{CC} = 5 V	$V_{CC} = 5 V \qquad 2.6$	2.6	3.3	4	2.9	3.3	3.8	V	
	Low-level output voltage		I _{OL} = 10 mA		0.1	0.25		0.1	0.15		
		V _{CC} = 15 V	I _{OL} = 50 mA		0.4	0.75		0.4	0.5	V	
VOL			I _{OL} = 100 mA		2	2.5		2	2.2		
VOL	Low-level output voltage		I _{OL} = 200 mA		2.5			2.5			
		V _{CC} = 5 V	I _{OL} = 5 mA		0.1	0.25		0.1	0.15		
		VCC = 3 V	I _{OL} = 8 mA		0.15	0.3		0.15	0.25		
		V _{CC} = 15 V	I _{OH} = -100 mA	12.75	13.3		13	13.3	3		
VOH	High-level output voltage	VCC = 13 V	I _{OH} = -200 mA		12.5			12.5		V	
		$V_{CC} = 5 V$	I _{OH} = -100 mA	2.75	3.3		3	3.3			
		Output low,	V _{CC} = 15 V		20	30		20	24	mA	
ICC	Supply current	No Load	V _{CC} = 5 V		6	12		6	10	11/7	
·UU		Output high, No load	V _{CC} = 15 V		18	26		18	20	nA	
			No load $V_{CC} = 5 V$	$V_{CC} = 5 V$		4	10		4	8	1173

NOTE 3: This parameter influences the maximum value of the timing resistors R_A and R_B in the circuit of Figure 1. For example, when $V_{CC} = 5 \text{ V}$, the maximum value is $R = R_A + R_B \approx 3.4 \text{ M}\Omega$, and for $V_{CC} = 15 \text{ V}$, the maximum value is $\approx 10 \text{ M}\Omega$.



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operating characteristics, V_{CC} = 5 V and 15 V

DADAME	TED	TEST	NE:	556, SA5	56		SE556		LINUT
PARAME	IER	CONDITIONS [†]	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
	Each timer, monostable§			1	3		0.5	1.5	
Initial error of timing interval‡	Each timer, astable¶	T _A = 25°C		2.25%			1.5%		
	Timer 1 — Timer 2			±1			±0.5		
	Each timer, monostable§	$T_A = MIN \text{ to MAX}$		50			30	100	ppm/°C
Temperature coefficient of timing interval	Each timer, astable¶			150			90		
	Timer 1 — Timer 2			±10			±10		
	Each timer, monostable§			0.1	0.5		0.05	0.2	
Supply voltage sensitivity of timing interval	Each timer, astable¶	T _A = 25°C		0.3			0.15		%/V
	Timer 1 — Timer 2			±0.2			±0.1		1
Output pulse rise time		C _L = 15 pF, T _A = 25°C		100	300		100	200	
Output pulse fall time		T _A = 25°C		100	300		100	200	ns

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] Timing interval error is defined as the difference between the measured value and the average value of a random sample from each process run.

\$ Values specified are for a device in a monostable circuit similar to Figure 2, with component values as follow: $R_A = 2 k\Omega$ to 100 k Ω , $C = 0.1 \mu$ F. \$ Values specified are for a device in an astable circuit similar to Figure 1, with component values as follow: $R_A = 1 k\Omega$ to 100 k Ω , $C = 0.1 \mu$ F.

APPLICATION INFORMATION



NOTE A: Bypassing the control-voltage input to ground with a capacitor may improve operation. This should be evaluated for individual applications.









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